# Product cleanliness (VCCN Guideline 12)

Msc. Olof Teulings





# Contents





### After this presentation, you will know

- Who I am and where I work
- What the VCCN is



- Contents of the guideline 12
- Practical interpretation by NTS
- Impact on design of the cleanroom

# MSc. Olof Teulings





# **Process & Cleanroom engineer @ NTS**

Over 10 years of experience in:

- Continuous improvement of
  - clean assembly
  - · clean room
- Layout and expansion of the cleanroom

Co-author of the VCCN guideline 12.

# **NTS**







# First-Tier Contract Manufacturer of (opto-) mechatronic systems and mechanical modules

- Semicon & Analytical markets
- High complexity products, Low Volume
- Complete chain
  - Development,
  - Precision components and frames
  - System integration
- Global presence (Europe, Asia, USA)
- Over 1700 employees
- Turnover of €350+ million

# NTS







### **Facilities**

- Cleanroom
  - over 5500 m<sup>2</sup> (ISO 5-8, AMC)
- Cleaning processes, a.o.
  - Alkaline cleaning
  - Vapour degreasing (in 2023)
  - Bake-out
  - Sensitive snowcleaning
- Laboratory, a.o.
  - Fast Micro + PMC
  - Sem-EDX
  - Sensitive RGA



# VCCN – What is the VCCN?





- Dutch society for Contamination Control
- Founded in 1988
- Over 500 members
- Active in different markets:
  - Micro-Nano
  - Health care
  - Pharma
  - Food
  - Space



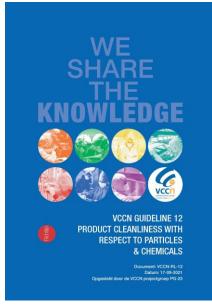


# Developing knowledge

ISO classification number (N)	Maximum concentration limits (particles/m³ of air) for particles equal to and larger than the considered sizes shown below										
	0.1 µm	0,2 μm	0,3 μm	0,5 μm	1 µm	5 μm					
ISO Class 1	10	2									
ISO Class 2	100	24	10	4							
ISO Class 3	1 000	237	102	35	8						
ISO Class 4	10 000	2 370	1 020	352	83						
ISO Class 5	100 000	23 700	10 200	3 520	832	29					
ISO Class 6	1 000 000	237 000	102 000	35 200	8 320	293					
ISO Class 7				352 000	83 200	2 930					
ISO Class 8				3 520 000	832 000	29 300					
ISO Class 9				35 200 000	8 320 000	293 000					

NOTE. Uncertainties related to the measurement process require that concentration data with no more than three significant figures be used in determining the classification level.









**Projects** 





# Transfering knowledge

Courses, Trainings and Workshops





**Technical** 



**Behaviour** 



**Cleaning** 

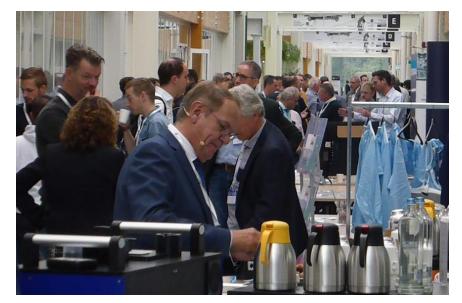


**Product cleanliness** 





# Sharing knowledge



**Excursions & Business fairs** 



**Conferences & Symposia** 



C<sup>2</sup> MGZN - Magazine



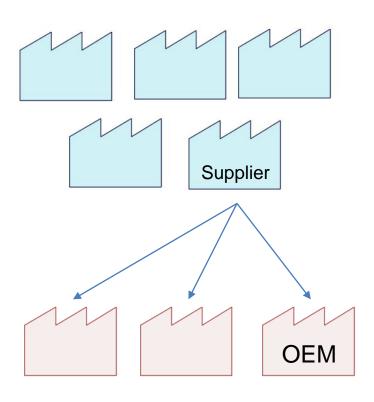
# Guideline 12

# Product cleanliness

with respect to Particles & Chemicals



# Guideline 12 – Why?



### Surface cleanliness for particles and chemicals

A lot of different suppliers deliver parts/modules to the same set of OEM's:

- Every OEM specifies cleanliness in its own way
- Every supplier produces and cleans in its own way

Is there not a common ground?

# Guideline 12: Product cleanliness

## Group organised by VCCN with OEM, Suppliers & Consultants































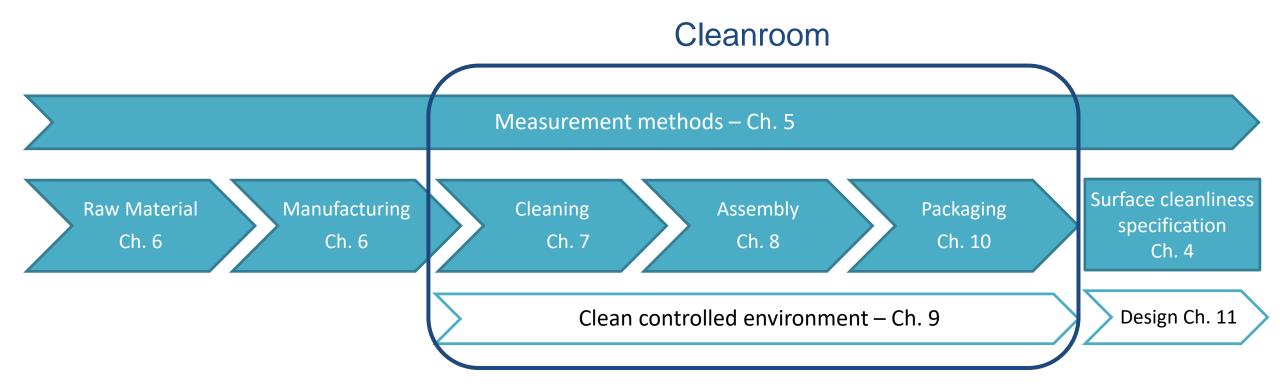




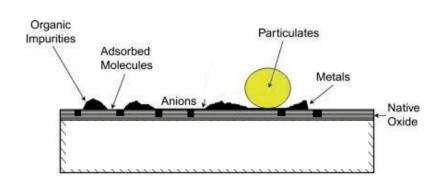




# Complete supply chain (Contents)



# Surface cleanliness specification (Chapter 4)



ISO SCC	Extre cle			ery ean	Cle	ean	Di	rty	
-1									]
-2									Dirty
-3									
-4									
-5									Clean
-6									
-7									
-8									Very clean
-9									
-10									Extremely
-11									clean
-12									orodin
	1	2	3	4	5	6	7	8	ISO SCP

#### • Use ISO14644 standards

other standards in Annex

#### Specification for:

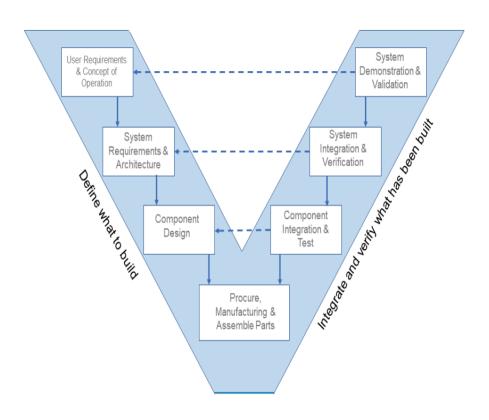
− Particles → SCP

- Chemicals  $\rightarrow$  SCC

Trace elements

Relation between Particles and Chemicals

# Surface cleanliness specification (Chapter 4)



- Design using the 'V-model'
  - Define and validate each phase
- Make cleanliness budgets
- Don't over or under specify
  - Use a risk assessment
- Specify with measurement method!

# Measurement methods (Chapter 5)

#### Particle measurement techniques

Size ra	Size range of particles on surfaces (µm)										
0.005	0.01	0.05	0.1	0.5	1	5	10	50	100	500	1000
								Visual c	ounting	•	•
							Stereo r	nicrosco	ру		
						Surface monitor					
					Microsco	cope (dark field)					
				Laser dif	fraction	particle a	analyser				
			Near fie	ear field microscopy							
			Light sca	Light scattering							
			Scannin	Scanning Electron Microscopy							
Transmission Electron Microscop											
Atomic	Atomic Force Microscopy										

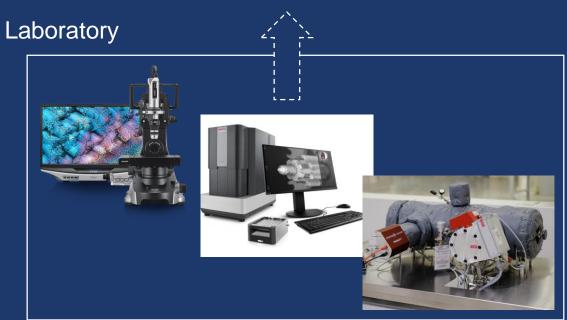
#### Chemical sampling techniques

Sampling procedure	Measured contaminant	Measurement technique	Industry/Laboratory
Gas purge	Organics,	Tenax-TD-GC, RGA	Industry
Gas Purge	Acids, bases	Ion chromatography, Ion Mobility	Laboratory
		Spectrometry, specific monitoring	
Leaching	Inorganics,	Ion chromatography, ICP-MS, Gas	Laboratory
	organics	Chromatography	
Leaching	Inorganics,	Weighing	Industry
	organics		
Witness plate	Inorganics,	ICP-MS, FTIR, XPS, AAS	Laboratory
	Organics		
C-tabs	Inorganics,	SEM-EDX,	Industry/Laboratory
	organics		
Moisture	Water	CRDS	Laboratory
Vacuum	Organics	RGA	Industry/Laboratory
extraction			

- Direct or indirect measurements
  - Indirect is removing with air, liquid or solid
- Industrial or laboratory methods
- Total overview in:
  - ISO 14644-9 (particles)
  - ISO 14644-10 (chemical)

#### Routine measurement







## **MEASUREMENT METHODS**

- Have a laboratory!
  - Be able to measure (more than)
     the OEM's demand

 Laboratory techniques are transferring (temporary) to Routine measurements

# Raw material & Manufacturing (Chapter 6)



#### Raw material

- Uniform
- Properties change for larger blocks...

#### Environment of manufacturing

- Separate materials for cross-contamination
- Air

## Handling, packaging & transport

- Gloves,
- Covered,
- markings



# Raw material & Manufacturing (Chapter 6)





### Machining

- Fluids quality
- Cross contamination previous products
- Fluids must be matched to cleaning process

#### Intermediate cleaning

Prevents drying in of fluids

#### Surface treatment

- Contamination can diffuse through the surface
- Cleanliness of treatment fluids





# **MACHINING**

Fluid control

- Environmental control
- Intermediate cleaning
- Everything with gloves, no exception

→ 1 FTE

# Cleaning (Chapter 7)





#### **Guide to choosing cleaning method:**

- 1. Object description
- 2. Cleanliness specification
- 3. Initial contamination level
- 4. other requirements
  - a.o. capacity, environment
- 5. Select cleaning methodology
- 6. Check material compatibility
- 7. Cleanliness validation
- 8. Validate cleaning methodology



# Cleaning (Chapter 7)

Particle removal	dirty		very clean		е	xtremel	y clean	
Technique	SCP 8	SCP 7	SCP 6	SCP 5	SCP 4	SCP 3	SCP 2	SCP 1
Mechanical cleaning								
Wiping	х	х	х	х				
Brushing/Sweeping	x	×	×					
Scraping/Abrading		×	×					
Grinding		×	×					
Fluidic cleaning								
Washing/Rinsing		х	х					
Compressed gas cleaning/rinsing		×	×					
Vacuum cleaning		×	×					
Acoustic cleaning			×	х				
1 Ultrasonic cleaning			×	x				
2 Megasonic cleaning			×	x				
Spray cleaning		х	x	x				
Vacuum cyclic nucleation				х	х			

Chemical removal	dirty		very clean			extremely clean		
Technique	SCC -1	SCC -2	SCC -3	SCC -4	SCC -5	SCC -6	SCC -7	SCC -8
Fluidic cleaning								
Washing/Rinsing	Х	х	х	х				
Compressed gas cleaning/rinsing	X	х	x	x				
Acoustic cleaning	x	х	х	x	х			
1 Ultrasonic cleaning	х	х	х	х	х			
2 Megasonic cleaning	×	х	x	x	х			
Spray cleaning	X	х	x	x	x			
Vacuum cyclic nucleation		х	х	х	x			

- Overview of cleaning methods and their achievable cleanliness level
  - Particles (SCP)
  - Chemicals (SCC)







#### **CLEANING**

- Keep improving cleaning Process
- Introduction of Sensitive snow cleaning (SCP 4, SCC -6)
- Validation of cleaning
- More processes

→ 1 FTE!

# Assembly (Chapter 8)





### Deposition contamination

Particle Deposition Rate (ISO 14644-17)

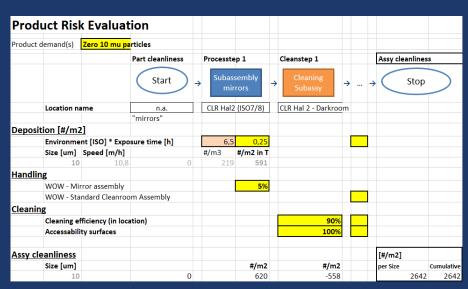
#### Assembly contamination

- Handling
- Assembly action (screw, glue, etc.)

# Assy cleaning

- Less cleaning methods available
- Product risk assessment



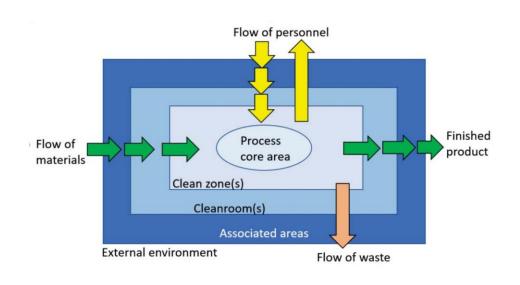




#### **ASSEMBLY**

- Measure deposition (ACP, PDR)
- Train & audit for Assembly
- Dark rooms for assy cleaning
- Do the product risk assessment!

# Contamination control (Chapter 9)



#### Air cleanliness

Particle/Chemical Deposition Rate calculations

$$PDRL = \frac{PDR(D) \cdot D}{10}$$

$$Cs(D) = PDR(D) \cdot T$$

$$N(D) = PDR(D) \cdot A \cdot T$$

#### Particle control solutions

- Installation
- Layout personnel & goods Locks
- Equipment
- Cleaning
- Way-of-Working



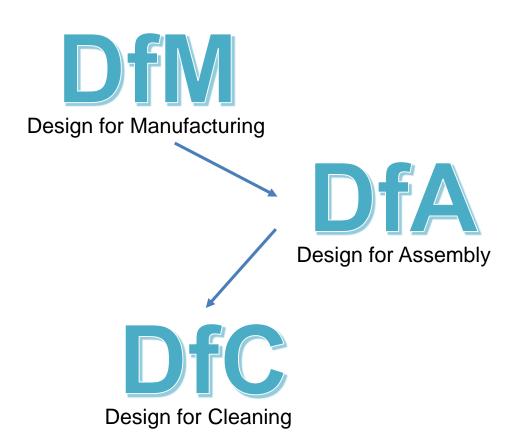




### **CONTAMINATION CONTROL**

- Keep measuring
- Organise responsibility
- Layout challenge:
  - Flexible (m²) vs Separation
- Continuous improvement
  - → 1 FTE!

# Design for Cleanliness (Chapter 10)



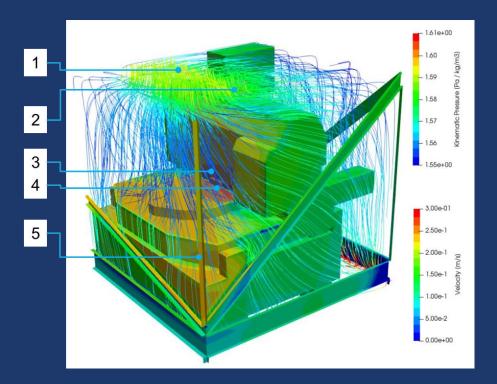
### Design considerations for Particles

- Low particle generation material
- Small surfaces
- Short exposure

#### Design considerations for Chemicals

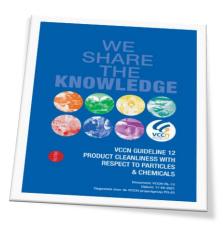
- Rules for UHV design
- Low outgassing materials
- Surface roughness
- Design for cleaning





### **DESIGN FOR CLEANLINESS**

- DfC training
- Outgassing calculations
- CFD simulations for particles





# vccn | WE SHARE THE KNOWLEDGE

# Closure

### **Process is the most important!**

Guideline 12 describes the process for the complete supply chain!

#### Cleanroom

- Cleaning processes will grow
- Labo is Needed
- Flexibility

### **Product cleanliness**

- Is a lot of work!
- Work together
  - Cleanliness Competence Team!

# Thank you for your attention,

Any questions?

